United States Patent [19]

Kida

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[45] **Date of Patent: ** Aug. 21, 1990**

[54] **PROBE FOR ELECTRONIC CLINICAL THERMOMETER**

[75] Inventor: **Kenichi Kida**, Tokyo, Japan

[73] Assignee: **Terumo Kabushiki Kaisha**, Tokyo, Japan

[**] Term: **14 Years**

[21] Appl. No.: **103,261**

[22] Filed: **Sep. 30, 1987**

[30] **Foreign Application Priority Data**

Jul. 31, 1987 [JP] Japan 62-30899

[52] **U.S. Cl.** **D10/60**

[58] **Field of Search** D10/52, 59, 60; 128/207.14, 736; 374/100, 106, 132, 151, 158, 159, 164, 170, 179, 185, 194, 208, 209

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[57] **CLAIM**

The ornamental design for a probe for electronic clinical thermometer, as shown and described.

DESCRIPTION

FIG. **1** is a top, front, right side perspective view of a probe for electronic clinical thermometer showing my new design;

FIG. **2** is a front elevational view;

FIG. **3** is a rear elevational view;

FIG. **4** is a right side elevational view, the left side elevational view being identical;

FIG. **5** is a top plan view;

FIG. **6** is a bottom plan view; and

FIG. **7** is an enlarged cross-sectional view as taken from line VII—VII FIG. **2** thereof.

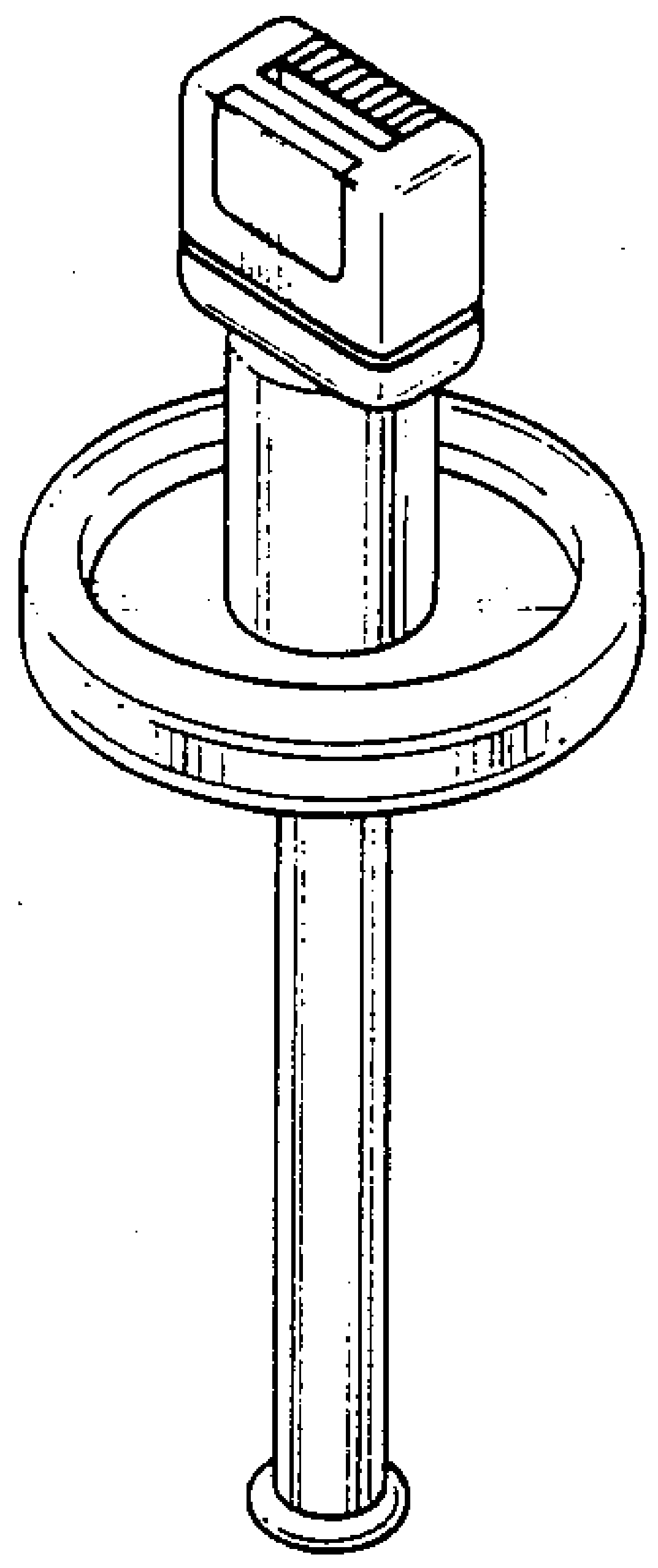

FIG. 1

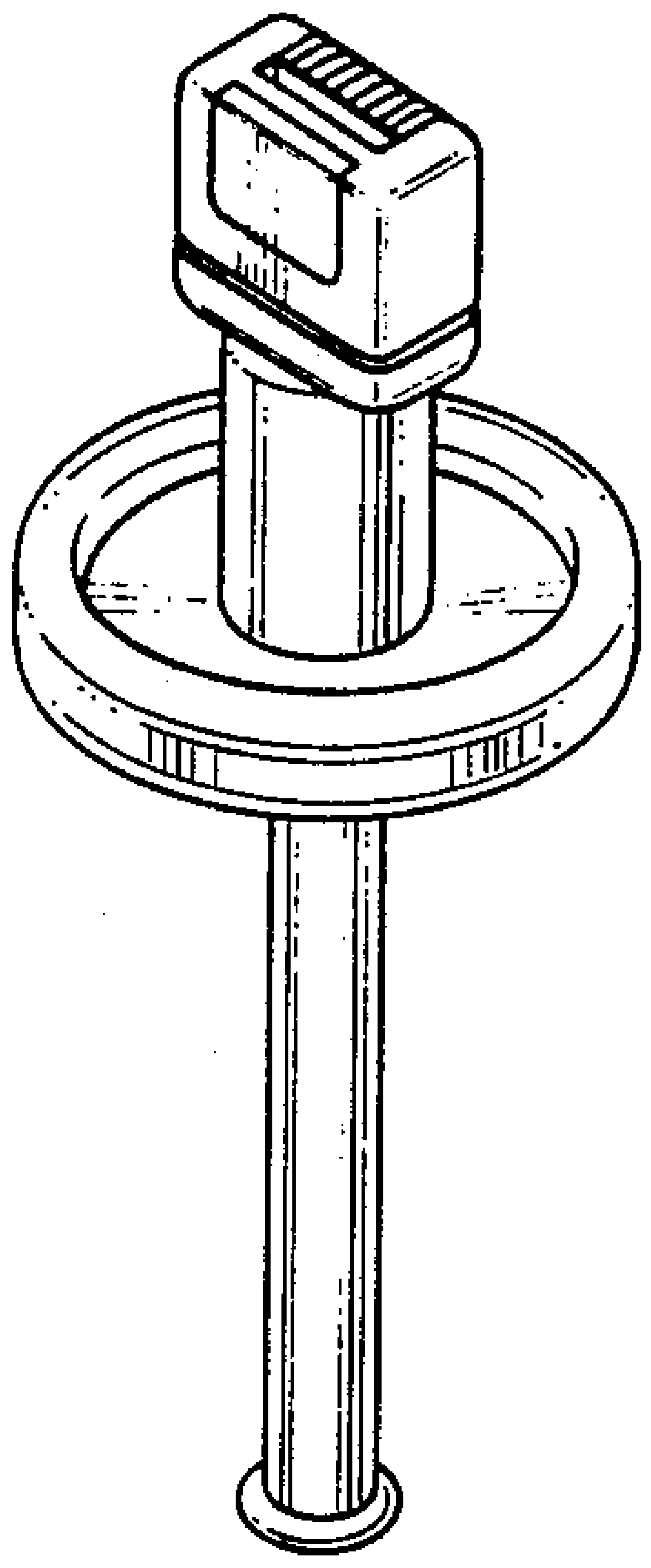

FIG. 2

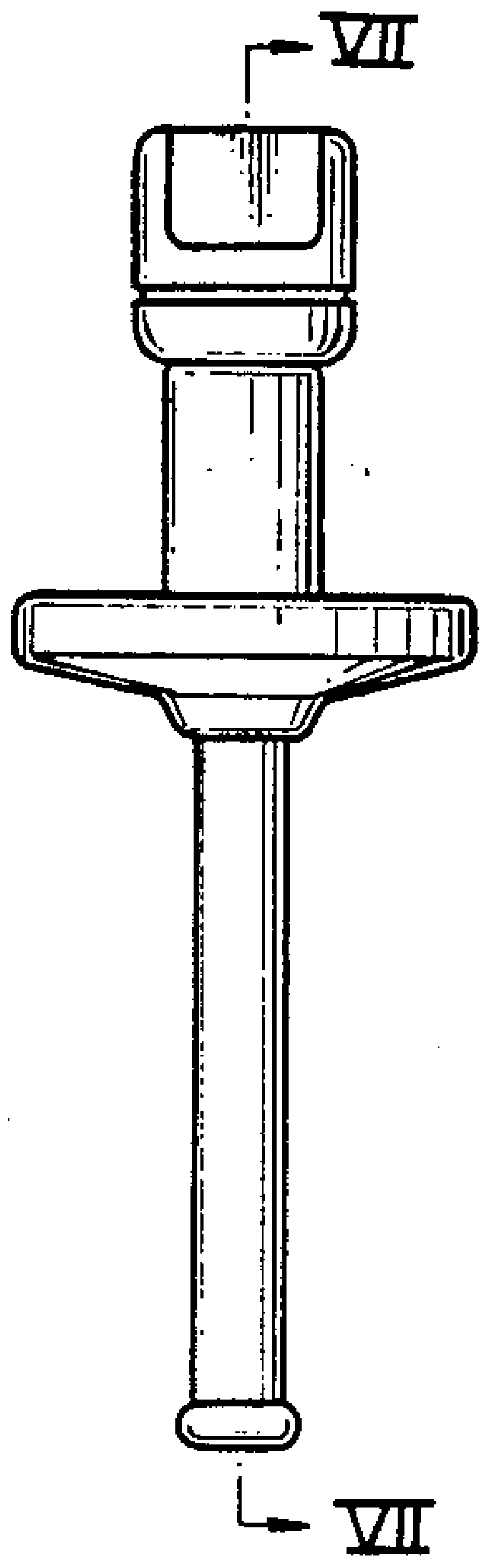

FIG. 3

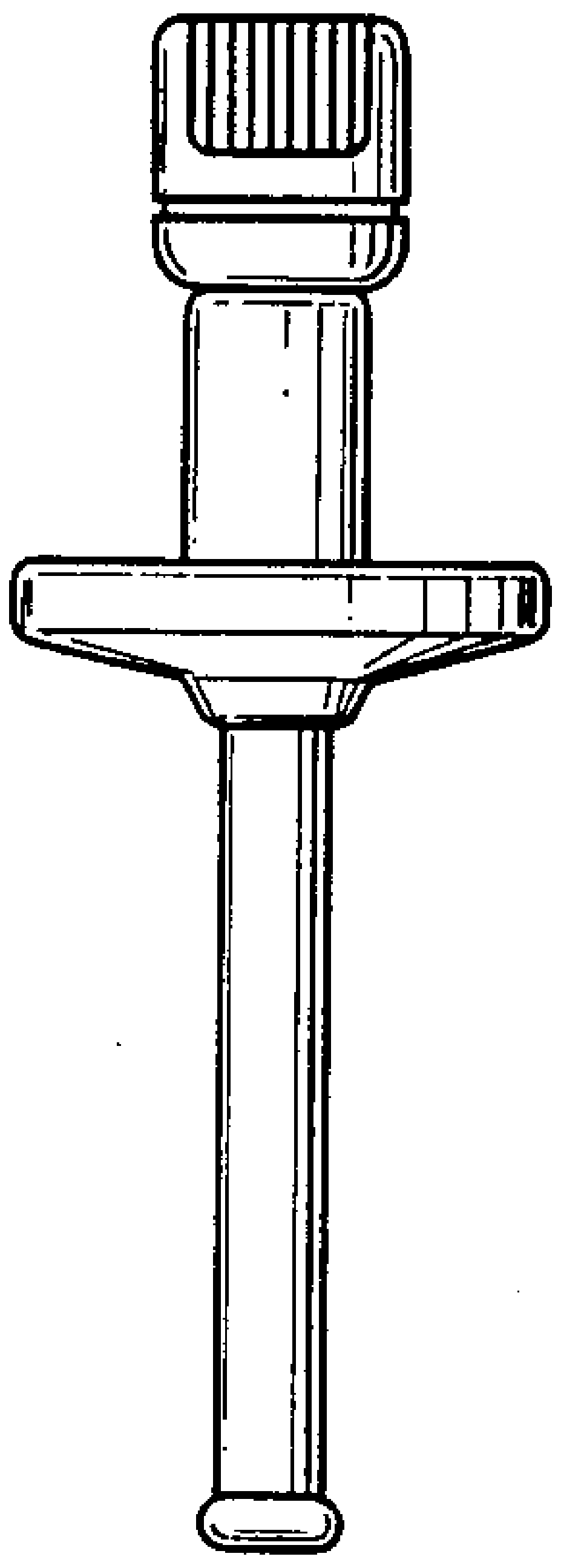

FIG. 4

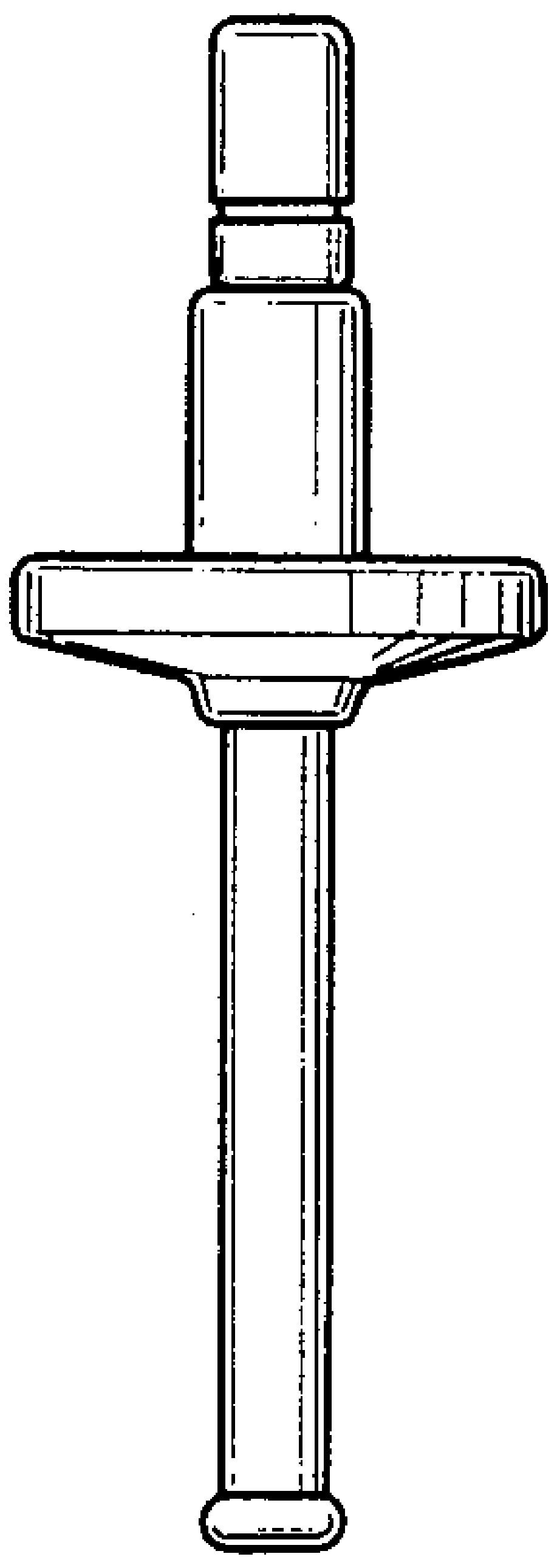

FIG. 5

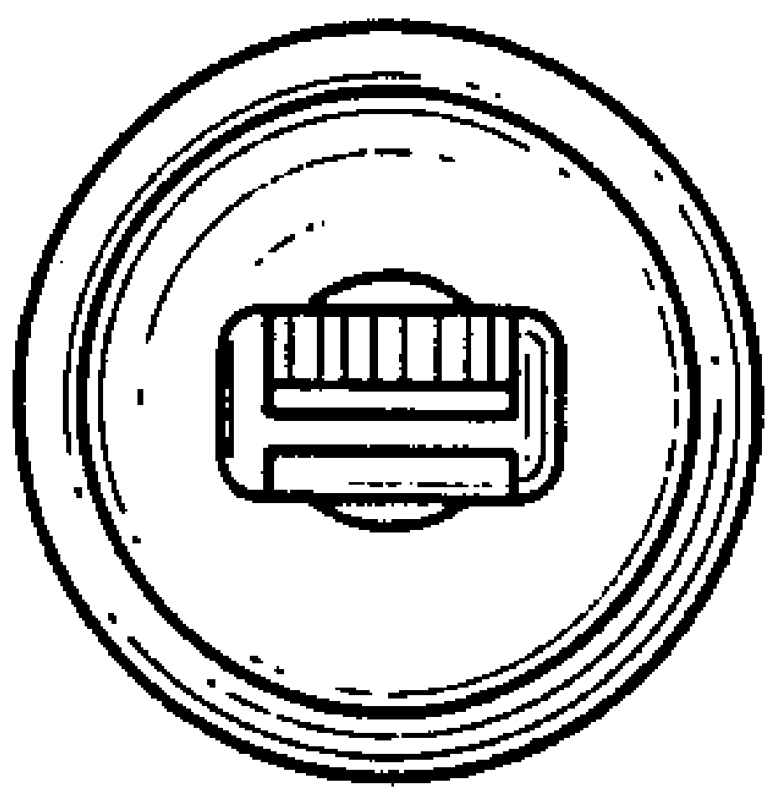

FIG. 6

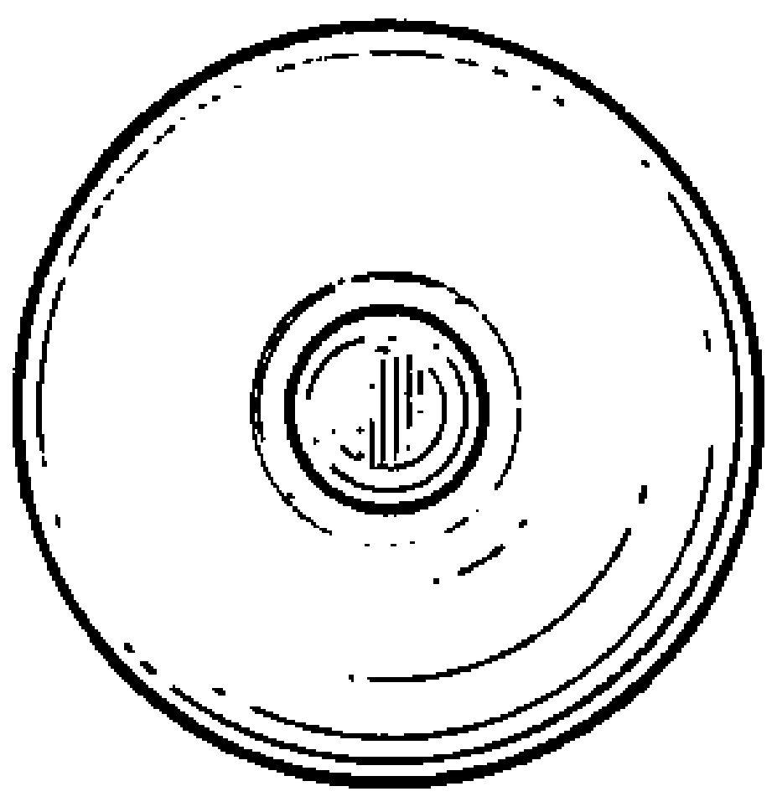

FIG. 7